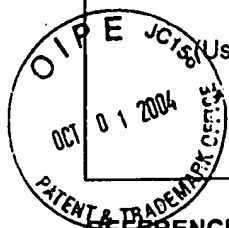


FORM PTO-1449 (Modified) LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT(S) INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)	ATTY. DOCKET NO. 02EK-105598	SERIAL NO. 10/808,665
	APPLICANT: Lidu Huang, et al.	
	FILING DATE: March 24, 2004	GROUP ART UNIT: 2877



REFERENCE DESIGNATION U.S. PATENT DOCUMENTS

EXAM'R INITIAL		DOCUMENT NUMBER	DATE	NAME	Class	Subclass	Filing Date If Appropriate
KG	A1	6,504,966	01/07/2003	Kato et al.	385	16	
	A2						
	A3						
	A4						

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EXAM'R INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	Subclass	TRANSLAT'N	
							yes	no
	B							
	B							

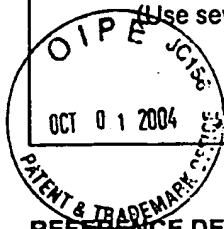
OTHER ART (Include Author, Title, Date, Pertinent Pages, Etc.)

KG	C1	"Silica Integrated Optical Circuits", edited by H. M. Presby, Section 2 "Fabrication", SPIE Milestone Series, vol. MS 125, pp. 43-149, 1996					
KG	C2	T. Fukano and I. Yamoguchi, "Simultaneous measurement of thickness and refractive indices of multilayers by a low-coherence confocal interference microscope", Opt. Lett., vol. 21, pp. 1942-1944, 1996					
KG	C3	G. J. Veldhuis, L.E. W. van Veen and P. V. Lambeck, "Integrated optical refractometer based on waveguide bend loss", IEEE J. Lightwave Technol., vl. 17, pp. 857-864, 1999					
KG	C4	D. C. Yin and Y. Inatomi, "Measurement of refractive index of GaP crystal over a large temperature range using interferometry", Cryst. Res. Technol., vol. 35, pp. 221-228, 2000					
KG	C5	T. Dennis, E. M. Gill and S. L. Gilbert, "Interferometric measurement of refractive-index change in photosensitive glass", Appl. Optics, vol. 40, pp. 1663-1667, 2001					
KG	C6	O. M. Efimov, L. B. Glebov and H. P. Andre, "Measurement of the induced refractive index in a photothermorefractive glass by a liquid-cell shearing interferometer", Appl. Optics, vol. 41, pp.1864-1870, 2002					

EXAMINER /Kara Geisel/ (12/26/2006)	DATE CONSIDERED
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	A						
	A						
	A						

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EXAM'R INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	Subclass	TRANSLAT'N	
							yes	no
	B							
	B							

OTHER ART (Include Author, Title, Date, Pertinent Pages, Etc.)

KG	C7	A. L. Glebov, L. Huang, S. Aoki, M. G. Lee and K. Yokochi, "Two dimensional microlens arrays in silica-on-silican planar lightwave circuit technology", Journal of Microlithography, Microfabrication, & Microsystems, vol 2, no. 4, pp. 309-318, 2003
KG	C8	Meticon Corp., "Model 2010 Prism Coupler Application Notes Measuring Index Anisotropy of Free-Standing Polymer Films," www.meticon.com/appli6.htm , 6/29/2004
KG	C9	Brother Gregory Investigates, "Measuring Refractive Index," www.brooklyn.cuny.edu/bc/ahp/CellBio/RefIndex/RI.Main.html , 6/30/2004
	C10	
	C11	
	C12	

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